# **Signetics**

# 8T95, 96, 97, 98 Hex Buffers/Inverters

High Speed Hex 3-State Buffers High Speed Hex 3-State Inverters Product Specification

### **Logic Products**

### DESCRIPTION

Each of the 3-state bus interface elements described herein has low current PNP inputs and is designed with Schottky TTL technology for ultra high speed. The devices are used to convert TTL/DTL or MOS/CMOS to 3-state TTL bus levels. For maximum systems flexibility, the 8T95 and 8T97 do so without logic inversion, whereas the 8T96 and 8T98 provide the logical complement of the input. The 8T95 and 8T96 feature a common control line for all six devices, whereas the 8T97 and 8T98 have control lines for four devices from one input and two from another input.

### **FUNCTION TABLE — 8T95**

	INPUTS	OUTPUT	
DIS <sub>1</sub>	DIS <sub>2</sub>	ı	Υ
L	L	L	L
L	L	Н	н
X	Н	Х	(Z)
Н	Х	X	(Z)

- H = HIGH voltage level
- L = LOW voltage level
- X = Don't care
- (Z) = HIGH impedance (off) state

### **FUNCTION TABLE — 8T96**

	INPUTS		OUTPUT
DIS <sub>1</sub>	DIS <sub>2</sub>		Ÿ
L	L	L	Н
L	L	Н	L
Х	Н	X	(Z)
Н	Х	X	(Z)

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
N8T95	8ns	65mA
N8T96	6.5ns	59mA
N8T97	8ns	65mA
N8T98	6.5ns	59mA

### **ORDERING CODE**

PACKAGES	COMMERCIAL RANGE V <sub>CC</sub> = 5V ±5%; T <sub>A</sub> = 0°C to +70°C
Plastic DIP	N8T95N, N8T96N N8T97N, N8T98N
Plastic SO	N8T97N, N8T98D

#### NOTE:

For information regarding devices processed to Military Specifications, see the Signetics Military Products Data Manual.

## INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	87
DIS	Input	1Sul
I	Input	1Sul
Y	Output	24Sul

#### NOTE

A unit load (Sul) is 50 µA IH and -2.0mA IL.

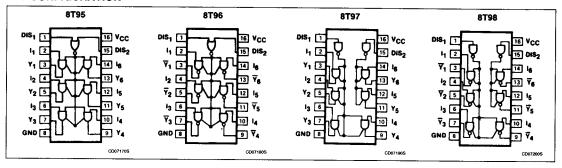
### **FUNCTION TABLE — 8T97**

INF	UTS	OUTPUT
DIS	ı	Y
L	L	L
L	H	н
Н	X	(Z)

### **FUNCTION TABLE — 8T98**

INP	UTS	OUTPUT
DIS	ı	Ÿ
L	L	Н
L	н	L
н	x	(Z)

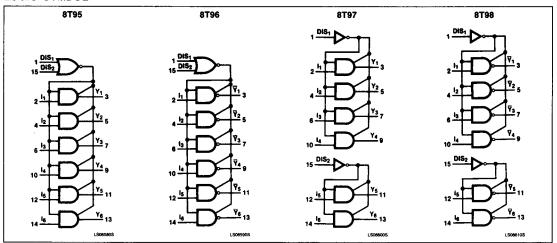
### PIN CONFIGURATION



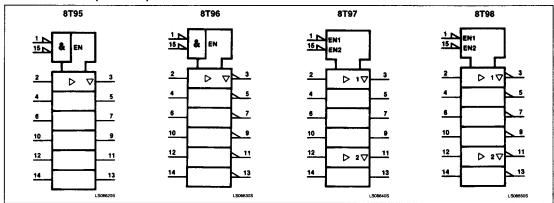
## Hex Buffers/Inverters

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### LOGIC SYMBOL



### LOGIC SYMBOL (IEEE/IEC)



## ABSOLUTE MAXIMUM RATINGS (Over operating free-air temperature range unless otherwise noted.)

	PARAMETER	S8T	N8T	UNIT
V <sub>CC</sub>	Supply voltage	7.0	7.0	٧
V <sub>IN</sub>	Input voltage	-0.5 to +5.5	-0.5 to +5.5	V
I <sub>IN</sub>	Input current	-30 to +5	-30 to +5	mA
loL	Continuous	100	100	mA
V <sub>OUT</sub>	Voltage applied to output in HIGH output state	-0.5 to +V <sub>CC</sub>	-0.5 to +V <sub>CC</sub>	٧
TA	Operating free-air temperature range	-55 to +125	0 to 70	°C

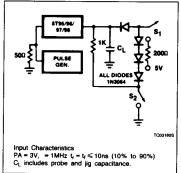
# Hex Buffers/Inverters

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### RECOMMENDED OPERATING CONDITIONS

	PARAMETER		8T			
PARAMETER		Min	Nom	Max	UNIT	
V <sub>CC</sub>	Supply voltage	4.75	5.0	5.25	V	
V <sub>IH</sub>	HIGH-level input voltage	2.0			V	
VIL	LOW-level input voltage			+0.8	V	
I <sub>IH</sub>	Input clamp current			-18	mA	
loh	HIGH-level output current			-5.2	v	
loL	LOW-level output current			48	mA	
T <sub>A</sub>	Operating free-air temperature	0		70	°C	

### **TEST CIRCUIT**



DC ELECTRICAL CHARACTERISTICS (Over recommended operating free-air temperature range unless otherwise noted.)

	PARAMETER	TEST CON	TEST CONDITIONS <sup>1</sup>		8T95/97		8T96/98	
	- ANAMETER	TEST CONDITIONS.		Min	Max	Min	Max	UNIT
VIH	Input HIGH voltage	Guaranteed input HIGH	threshold voltage	2.0		2.0		V
VIL	Input LOW voltage	Guaranteed input LOW	threshold voltage		0.8	_	0.8	V
$V_{IK}$	Input clamp diode voltage	V <sub>CC</sub> = MIN, I <sub>IK</sub> = -12mA	V <sub>CC</sub> = MIN, I <sub>IK</sub> = -12mA		-1.5		-1.5	V
V <sub>BD</sub>	Input breakdown voltage	V <sub>CC</sub> = MAX, I <sub>I</sub> = 1mA	V <sub>CC</sub> = MAX, I <sub>I</sub> = 1mA			5.5		V
V <sub>OH</sub>	HIGH-level output voltage	V <sub>CC</sub> = MIN, I <sub>OH</sub> = ~5.2mA		2.4		2.4		V
VOL	LOW-level output voltage	V <sub>CC</sub> = MIN, I <sub>OL</sub> = 48mA		1	0.53		0.53	v
ЮZН	Off-state output current, HIGH-level voltage applied	V <sub>CC</sub> = MAX, V <sub>O</sub> = 2.4V			40		40	μΑ
lozL	Off-state output current, LOW-level voltage applied	$V_{CC} = MAX, V_O = 0.5V$	$V_{CC} = MAX, V_O = 0.5V$		-40		-40	μΑ
l <sub>IH</sub>	HIGH-level input current	$V_{CC} = MAX$ , $V_I = 2.4V$			40		40	μΑ
l <sub>IL</sub>	LOW-level input current	V 444V V 0.514	Disable = 0.5V	1	-400		-400	μА
'IL	LOW-level input current	nput current $V_{CC} = MAX, V_1 = 0.5V$			-40		-40	μΑ
los	Short-circuit output current <sup>2</sup>	V <sub>CC</sub> = MAX		-40	-115	-40	-115	mA
Icc	Supply current (total)	V <sub>CC</sub> = MAX			98		89	mA

#### NOTES

<sup>1.</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.

<sup>2.</sup> I<sub>OS</sub> is tested with V<sub>OUT</sub> = + 0.5V and V<sub>CC</sub> = V<sub>CC</sub> MAX + 0.5V. Not more than one output should be shorted at a time and duration of the short circuit should not exceed one second.

<sup>3.</sup>  $V_{OL} = +0.45V$  MAX for S8T at  $T_A = +125$ °C only.

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## AC ELECTRICAL CHARACTERISTICS $T_{\text{A}} = 25^{\circ}\text{C}, \ V_{\text{CC}} = 5.0\text{V}$

			8T95/97 R <sub>L</sub> = 200Ω		8T96/98 R <sub>L</sub> = 200Ω		UNIT
	PARAMETER	TEST CONDITIONS					
			Min	Max	Min	Max	
t <sub>PLH</sub>	Propagation delay Data inputs to data outputs	S <sub>1</sub> , S <sub>2</sub> are closed, C <sub>L</sub> = 50pF		12		11	ns
t <sub>PHL</sub>	Propagation delay Data inputs to data outputs	S <sub>1</sub> , S <sub>2</sub> are closed, C <sub>L</sub> = 50pF		13		10	ns
t <sub>PZH</sub>	Disable to outputs High Z to logic "1"	S <sub>1</sub> is open, S <sub>2</sub> is closed, C <sub>L</sub> = 50pF		25		22	ns
t <sub>PZL</sub>	Disable to outputs High Z to logic ''0''	S <sub>1</sub> is closed, S <sub>2</sub> is open, C <sub>L</sub> = 50pF		25		24	ns
t <sub>PHZ</sub>	Disable to outputs Logic "1" to high Z	S <sub>1</sub> , S <sub>2</sub> are closed, C <sub>L</sub> = 5pF		10		10	ns
t <sub>PLZ</sub>	Disable to outputs Logic "0" to high Z	S <sub>1</sub> , S <sub>1</sub> are closed, C <sub>L</sub> = 5pF		12		16	ns

### **AC WAVEFORMS**

